Şe	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/660,698	OHISHI ET AL.
Examiner	Art Unit
Fikremariam Yalew	2136

•	SEARCHED		
Class	Subclass	Date	Examiner
380	200	9/17/2007	FA
713	182	9/17/2007	FA
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
,	DATE	EXMR
East(updated classification search and text search)	9/17/2007	FA
IEEE	9/17/2007	FA
Inventor search	9/17/2007	FA
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